2SD2185G

Silicon NPN epitaxial planar type

For low-frequency output amplification Complementary to 2SB1440G

■ Features

- Low collector-emitter saturation voltage V_{CE(sat)}
- Mini Power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V_{CBO}	50	V	
Collector-emitter voltage (Base open)	V_{CEO}	50	V	
Emitter-base voltage (Collector open)	V_{EBO}	5	V	
Collector current	$I_{\rm C}$	3	A	
Peak collector current	I_{CP}	4	A	
Collector power dissipation *	P _C	1	W	
Junction temperature	Tj	150	°C	
Storage temperature	T_{stg}	-55 to +150	°C	

Note) *: Printed circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

■ Package

- Code MiniP3-F2
- Pin Name
 - 1: Base
 - 2: Collector
 - 3: Emitter
- Marking Symbol: 1H

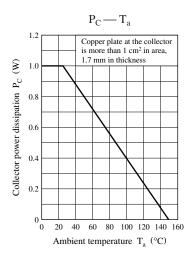
■ Electrical Characteristics T_a = 25°C ± 3°C

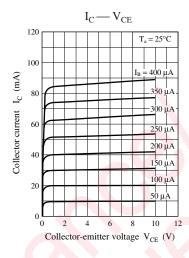
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V_{CBO}	$I_C = 10 \mu A, I_E = 0$	50			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = 1 \text{ mA}, I_B = 0$	50			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_E = 10 \mu A, I_C = 0$	5			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 20 \text{ V}, I_{E} = 0$			0.1	μΑ
Forward current transfer ratio	h _{FE1} *	$V_{CE} = 2 \text{ V}, I_{C} = 200 \text{ mA}$	120		340	_
	h _{FE2}	$V_{CE} = 2 \text{ V}, I_{C} = 1.0 \text{ A}$	80			
Collector-emitter saturation voltage	V _{CE(sat)}	$I_C = 1 \text{ A}, I_B = 50 \text{ mA}$		0.15	0.30	V
Base-emitter saturation voltage	V _{BE(sat)}	$I_C = 1 \text{ A}, I_B = 50 \text{ mA}$		0.85	1.20	V
Transition frequency	f_T	$V_{CB} = 10 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance (Common base, input open circuited)	C _{ob}	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		20	35	pF

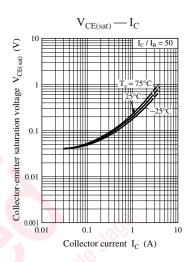
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

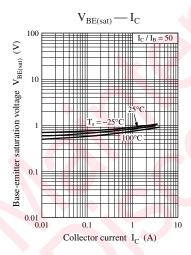
2. *: Rank classification

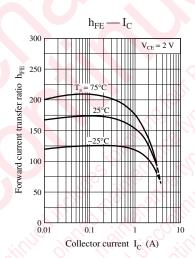
Rank	R	S
h_{FE1}	120 to 240	170 to 340

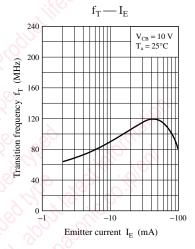


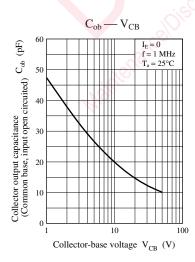






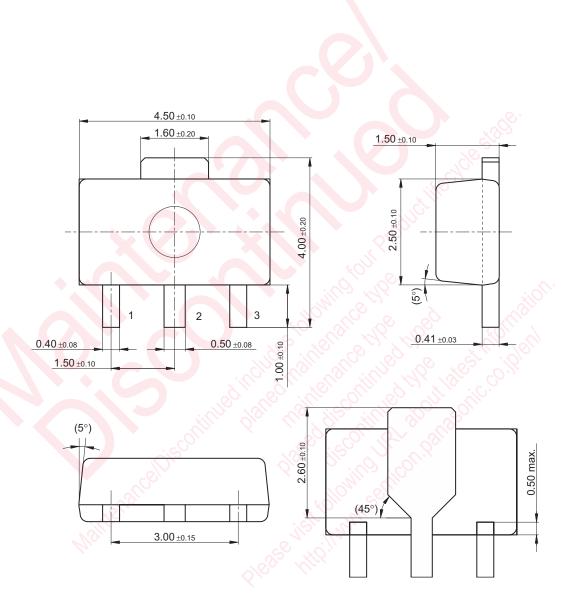






2 SJD00342AED

MiniP3-F2 Unit: mm



SJD00342AED 3

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